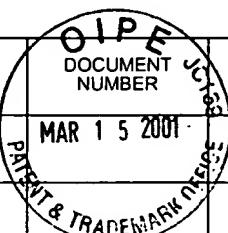


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FORM PTO-1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 35C.14179	APPLICATION NO. 09/722,454			
APPLICANT YOUICHI ANDO, ET AL.			FILING DATE November 28, 2000	GROUP Unassigned			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	TYPE	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>MWz</i>	5 2001	5066883	11/91	Yoshioka, et al.	313	309	
<i>MWz</i>	TRADEMARK OFFICE	5528108	6/96	Cisneros	315	169.3	
<i>MWz</i>		5569974	10/96	Morikawa, et al.	313	310	
<i>MWz</i>		5682085	10/97	Suzuki, et al.	315	169.1	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>MWz</i>	EP	0660357	6/95	Europe	—	—	
<i>MWz</i>	EP	1-31332	2/89	Japan	—	—	Abstract
<i>MWz</i>	JP	2-257551	10/90	Japan	—	—	Abstract
<i>MWz</i>	JP	3-55738	3/91	Japan	—	—	Abstract and USP 5,569,974
<i>MWz</i>	JP	4-28137	1/92	Japan	—	—	Abstract and USP 5,692,085
<i>MWz</i>	JP	7-235255	9/95	Japan	—	—	Abstract and EPA 660357
<i>MWz</i>	JP	8-106847	6/97	Japan	—	—	Abstract and USP 5,528,108
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>MWz</i>	•	Meyer, et al.; "Recent Development on 'Microtips' Display At Leti"; Tech. Dig. of IVMC 91, Nagahama 1991, pp. 6-9.					
<i>MWz</i>	○	Hartwell, et al.; "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films"; Tech. Dig. 1 EDM, Tech. Pig., Dec. 1-3, 1975, Wash. D.C., pp. 519-521 (1976).					
<i>MWz</i>	○	Spindt, et al.; "Physical Properties Of Thin-Film Field Emission Cathodes With Molybdenum Cones"; J. Appl. Phys. Vol. 47, No. 12, Dec. 1976, pp. 5248-5263.					
<i>MWz</i>	•	C.A. Mead; "Operation Of Tunnel-Emission Devices"; J. Appl. Phys. Vol. 32, No. 4, April 1961, pp. 646-652.					
<i>MWz</i>	○	Elinson, et al.; "The Emission Of Hot Electrons And The Field Emission Of Electrons From Tin Oxide"; Radio Engineering and Electronic Physics, Vol. 10, pp. 1290-1296, (1965).					
EXAMINER	<i>Maurice Antigny</i>		DATE CONSIDERED	9/23/03			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FORM PTO-1449 (modified)			ATTY DOCKET NO. 35C.14179		APPLICATION NO. 09/722,454		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPLICANT YOUICHI ANDO, ET AL.				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			FILING DATE November 28, 2000	GROUP Unassigned			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER 	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>MWZ</i>	<i>c</i>	G. Dittmer, "Electrical Conduction And Electron Emission Of Discontinuous Thin Films"; Thin Solid Films, Vol. 9, pp. 317-328 (1972).					
<i>MWZ</i>	<i>r</i>	Dyke, et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. III, Academic Press, 89-184 (1956).					
<i>CWZ</i>	<i>b</i>	Araki, et al., "Electroforming and Electron Emission of Carbon Thin Films"; J. Vac. Soc. Japan, Vol. 26, No. 1, pp. 22-29 (1981).					
EXAMINER <i>Mariachi pmwz</i>			DATE CONSIDERED <i>9/23/03</i>				

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FORM PTO 1449 (modified)		ATTY DOCKET NO. 35C.14179		APPLICATION NO. 09/722,454			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT YOUICHI ANDO, ET AL.					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE November 28, 2000		GROUP 2879			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>M. Stg</i>		High Voltage Technology", Electric Institute, Ohm Company, pages 38, 39 (1981).					
EXAMINER	<i>Mariceli Santiago</i>		DATE CONSIDERED		<i>9/23/03</i>		

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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